EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	15	kazunari near2 kurita.in.	EPO; JPO; DERWENT	OR	ON	2007/07/16 09:43
S2	36	shinsuke near2 sadamitsu.in.	EPO; JPO; DERWENT	OR	ON	2007/07/11 12:53
S3	61	hiroyuki near2 takao.in.	EPO; JPO; DERWENT	OR	ON	2007/07/11 12:54
S4	9	masataka near2 hourai.in.	EPO; JPO; DERWENT	OR	ON	2007/07/11 12:54
S5	114	S1 or S2 or S3 or S4	EPO; JPO; DERWENT	OR	ON	2007/07/11 13:06
S6	2	("6129787").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:06
S7	2	("6277193").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:06
S8	2	("6641888").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:06
S9	2	("6803242").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:06
S10	2	("7220308").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:07

S11	2	("7226571").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:07
S12	2	("6245430").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:07
S13	2	("6365461").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:07
S14	1	("re39173").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:07
S15	2	("6905771").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/11 13:07
S16	2	("6544656").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/16 09:43
S17	2	("20020179003").PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/16 09:44

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S18	1	10/009910	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:06
S19	7	"2004008521"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:08
S20	4	"2003092065"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:19
S21	0	EP1325178	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:19
S22	12	"1325178"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:19
S23	33	"224986"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:20
S24	2	"200224986"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:28

S25	9	"1229155"	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:29
S26	59	(silicon near2 wafer) and ((czochralski or cz) near2 method) and (oxygen near2 concentration) and (carbon near2 concentration) and resistivity and temperature	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 10:36
S27	749504	(("117") or ("257") or ("428") or ("438")).CLAS.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/07/16 10:38
S28	58	S26 and S27	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 11:07
S29	13	S28 and (epitax$3 near2 wafer) and (soi near2 wafer)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 11:21
S30	1	S28 and (heat-up near2 rate)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 11:22
S31	9	S28 and (heat near2 rate)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 11:22

S32	47	(US-20020179003-$ or US-20050253221-$ or US-20050250349-$ or US-20050005841-$ or US-20040166684-$ or US-20030192469-$ or US-20030175532-$ or US-20030164139-$ or US-20030008435-$ or US-20020189532-$ or US-20020179006-$ or US-20030136961-$ or US-20070066033-$ or US-20020142171-$).did. or (US-6277193-$ or US-RE39173-$ or US-6365461-$ or US-6641888-$ or US-6245430-$ or US-6129787-$ or US-7220308-$ or US-6803242-$ or US-7226571-$ or US-6905771-$ or US-6544656-$ or US-6548886-$ or US-6277501-$ or US-6206961-$ or US-5674756-$).did. or (WO-9825299-$ or WO-3092065-$ or WO-2004008521-$ or EP-1501122-$ or EP-1542269-$ or EP-1677344-$).did. or (JP-11021200-$ or JP-2004006615-$ or JP-2005123351-$ or JP-2005050942-$ or JP-2005294694-$ or JP-2005145744-$ or JP-2005175390-$ or JP-2005322712-$ or JP-2006073580-$ or JP-2006269896-$).did. or (WO-2004008521-$ or WO-2003092065-$).did.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/16 14:07
S33	13	S32 and (oxygen near2 donor)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/16 17:24
S34	16	S32 and (resistivity with "100")	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/16 14:12
S35	2	S32 and (bond with wafer)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/16 15:44

S36	47	(US-20020179003-$ or US-20050253221-$ or US-20050250349-$ or US-20050005841-$ or US-20040166684-$ or US-20030192469-$ or US-20030175532-$ or US-20030164139-$ or US-20030008435-$ or US-20020189532-$ or US-20020179006-$ or US-20030136961-$ or US-20070066033-$ or US-20020142171-$).did. or (US-6277193-$ or US-RE39173-$ or US-6365461-$ or US-6641888-$ or US-6245430-$ or US-6129787-$ or US-7220308-$ or US-6803242-$ or US-7226571-$ or US-6905771-$ or US-6544656-$ or US-6548886-$ or US-6277501-$ or US-6206961-$ or US-5674756-$).did. or (WO-9825299-$ or WO-3092065-$ or WO-2004008521-$ or EP-1501122-$ or EP-1542269-$ or EP-1677344-$).did. or (JP-11021200-$ or JP-2004006615-$ or JP-2005123351-$ or JP-2005050942-$ or JP-2005294694-$ or JP-2005145744-$ or JP-2005175390-$ or JP-2005322712-$ or JP-2006073580-$ or JP-2006269896-$).did. or (WO-2004008521-$ or WO-2003092065-$).did.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/16 17:24
S37	8	S36 and ((oxygen near2 donor) with concentration)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/07/16 17:24
S38	59	(silicon near2 wafer) and ((czochralski or cz) near2 method) and (oxygen near2 concentration) and (carbon near2 concentration) and resistivity and temperature	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/16 17:47